

## *State-of-the-Art Physical Failure Analysis Capabilities*



Nanolab Technologies offers Full Backside Preparation, Construction Analysis, Competitive Analysis, Cross-Section Preparation & Ultra High Resolution Documentation, Deprocessing, Decap, Deep UV Microscopy, Optical Microscopy, DualBeam FIBSEM, Root Cause Failure Analysis, FIB, SEM, and TEM Services.

Our Engineering Expertise combined with a State-of-the-Art Tool Set offers our customers an unparalleled one stop solution for comprehensive Failure Analysis.

For information or to arrange a demonstration please contact the New Pioneers in Failure Analysis:

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